

Electronic Supplementary Information for:

Average Collision Velocity of Single Yeast Cells during Electrochemically Induced Impacts

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Microscopic image and diameter distribution of yeast cells

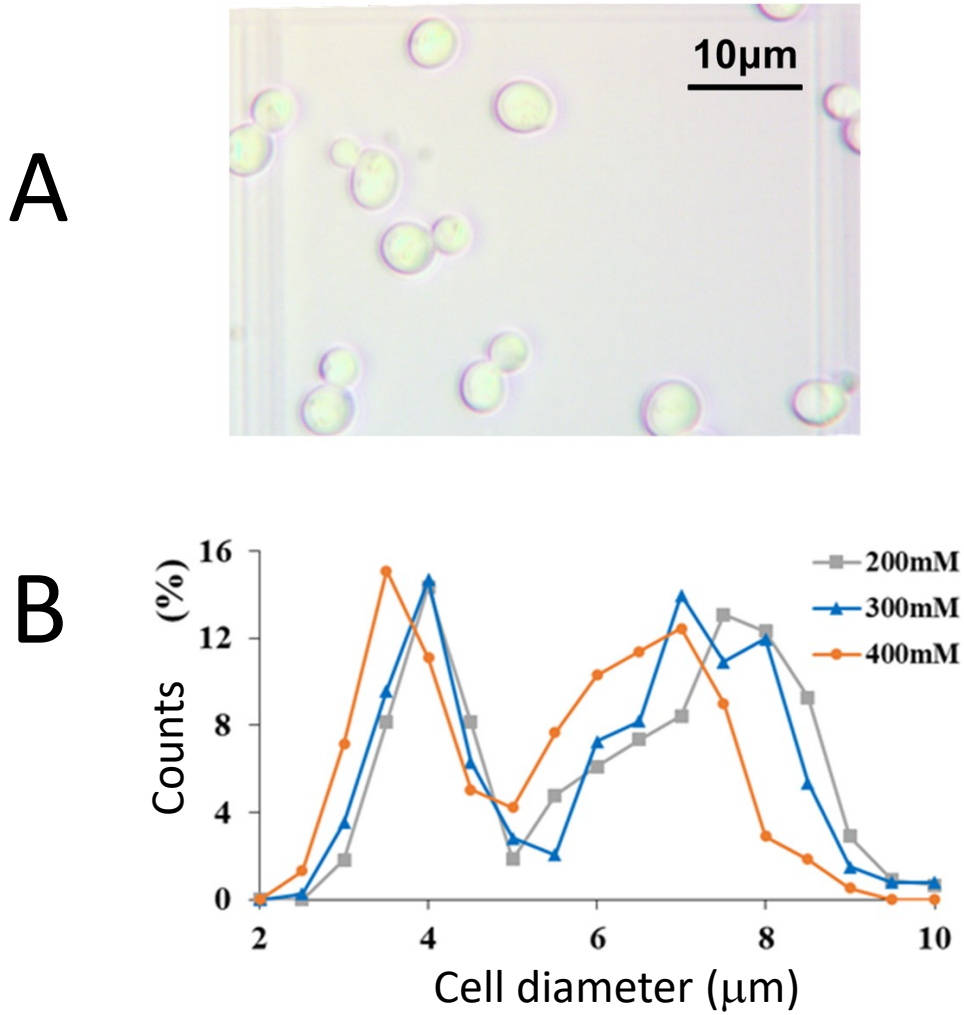


Figure S1. A) Microscopic image of yeast cells in solution of 100mM potassium chloride (KCl) and 400mM ferrocyanide (FCN). B) Size distribution of cells with increasing ferrocyanide FCN concentration.

Microscopic image of 12.5 μm ultramicroelectrode (UME) and CVs of increasing ferrocyanide (FCN) and UME radius (r_e)

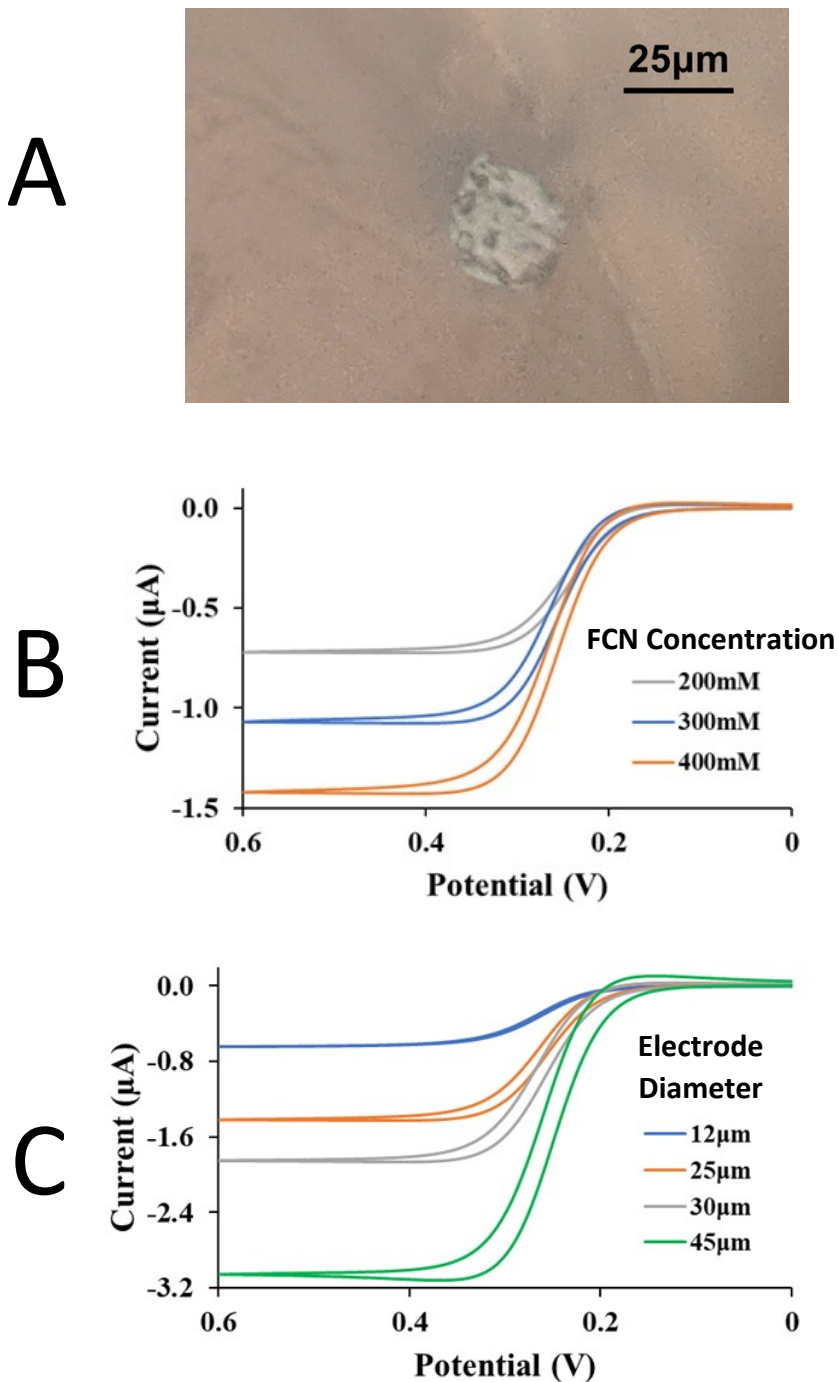
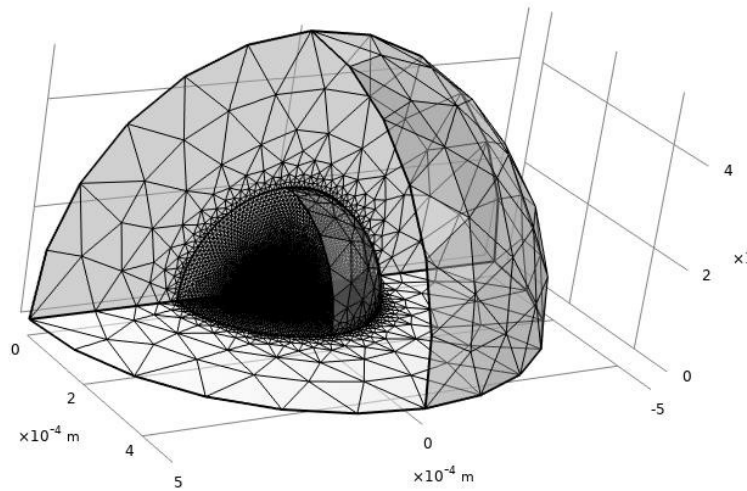


Figure S2. A) Microscopic image of platinum UME $r_e = 12.5 \mu\text{m}$. CV of B) 100mM KCl and UME $r_e = 12.5 \mu\text{m}$ with increasing FCN concentration and C) 100mM KCl and 400mM FCN with increasing UME.

Inner domain, outer domain, and particle meshing for finite element simulation

Domain

A



Particle Generation

B

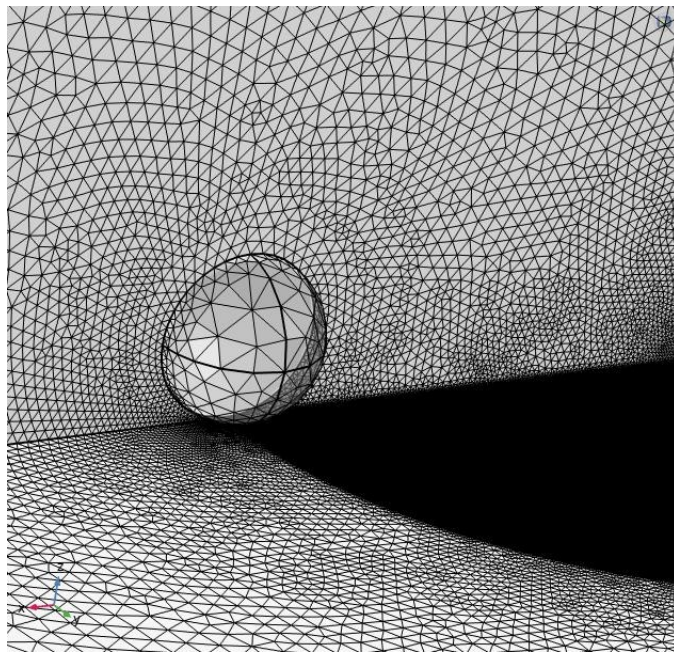
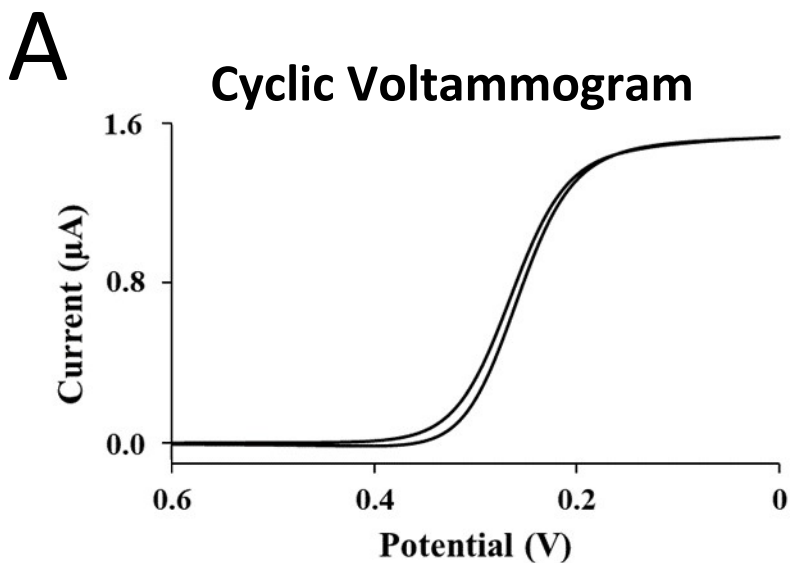


Figure S3. Meshing of A) 200 μm radius inner domain and B) 500 μm radius outer domain with 2 μm radius insulating sphere on edge of UME $r_e = 12.5 \mu\text{m}$.

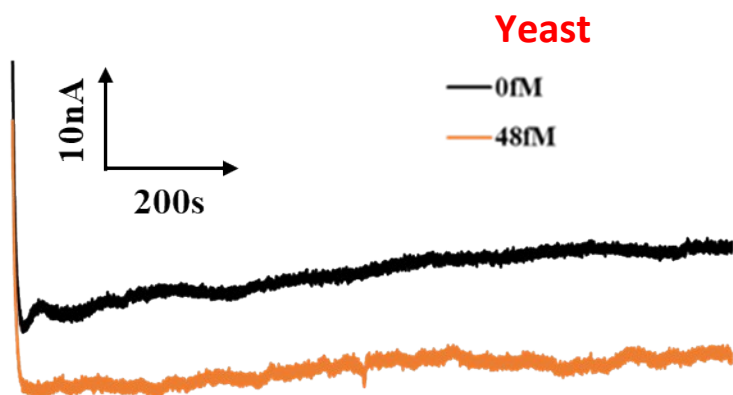
CV and *i-t* response of ferricyanide $\text{Fe}(\text{CN})_6^{3/4+}$ reduction



12.5 μm UME 400mM
100mM KCl ferricyanide

B

***i-t* Plots**



12.5 μm UME 400mM ferricyanide
100mM KCl +0V vs Ag/AgCl

Figure S4. A) CV and B) *i-t* response with 0fM (black) and 48fM (orange) yeast cells. 100mM KCl and 400mM FeCN^+ using UME $r_e = 12.5 \mu\text{m}$.

Simulated Δi -values for increasing r_e and cell radius (r_c)

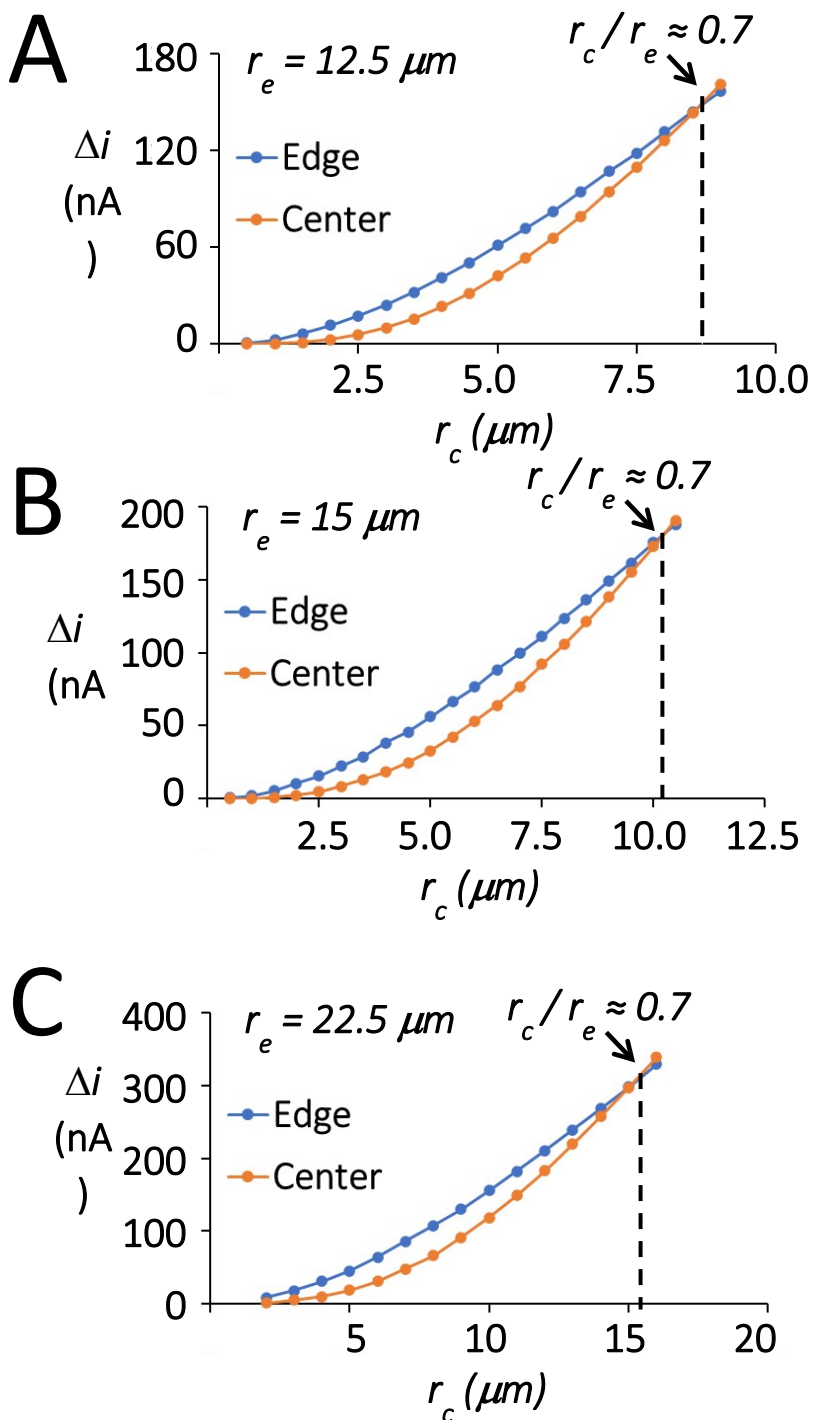


Figure S5. Simulated Δi -values (center and edge) for a UME $r_e =$ A) $12.5 \mu\text{m}$, B) $15 \mu\text{m}$, and C) $22.5 \mu\text{m}$. Dashed line shows r_c -value at which both equalize.

Simulated geometric factor (F_g)-values for increasing r_c/r_e ratio

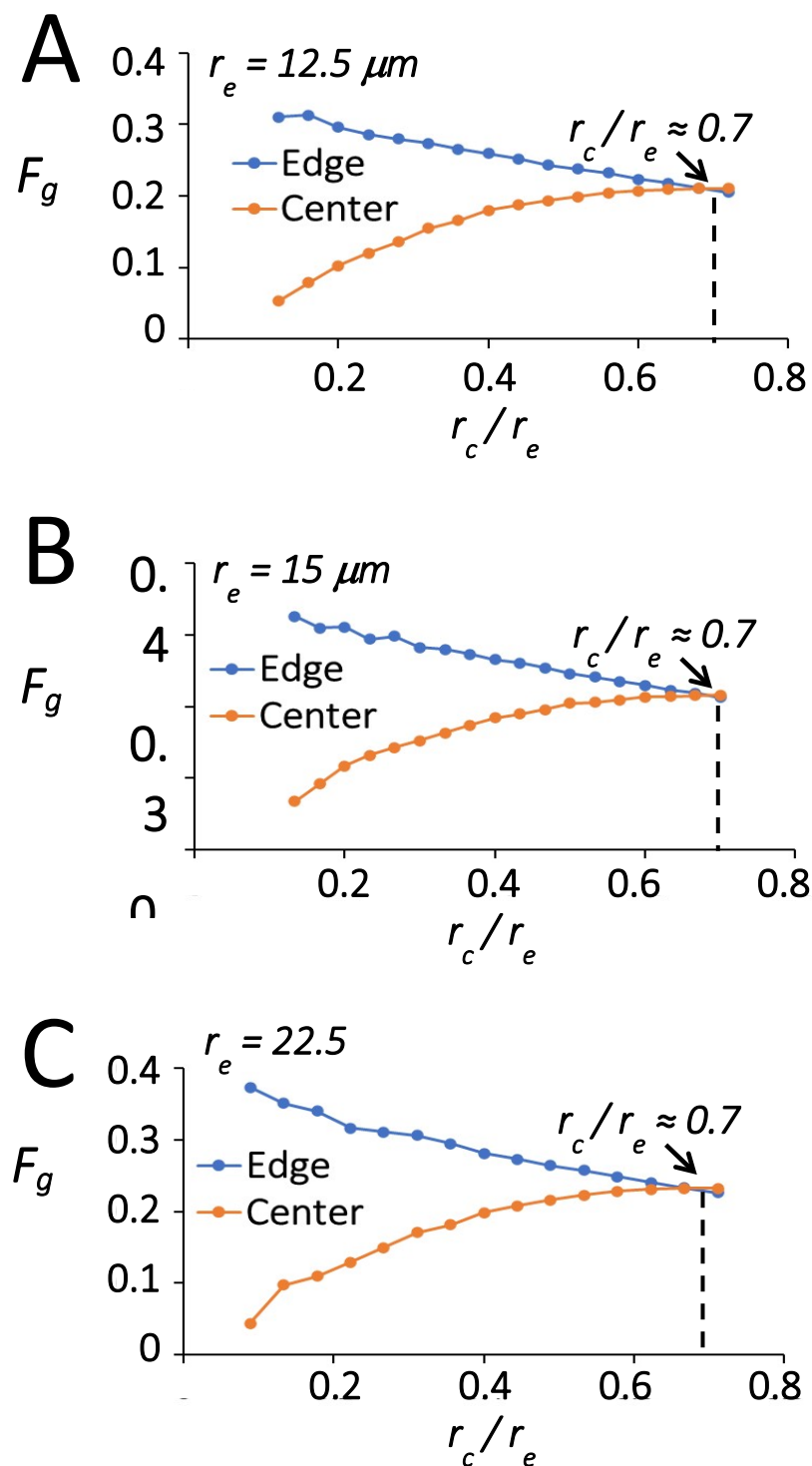


Figure S6. Simulated F_g -values (center and edge) for a UME $r_e =$ A) $12.5 \mu\text{m}$, B) $15 \mu\text{m}$, C) $22.5 \mu\text{m}$.

Redox flux profiles with increasing FCN concentration and r_e

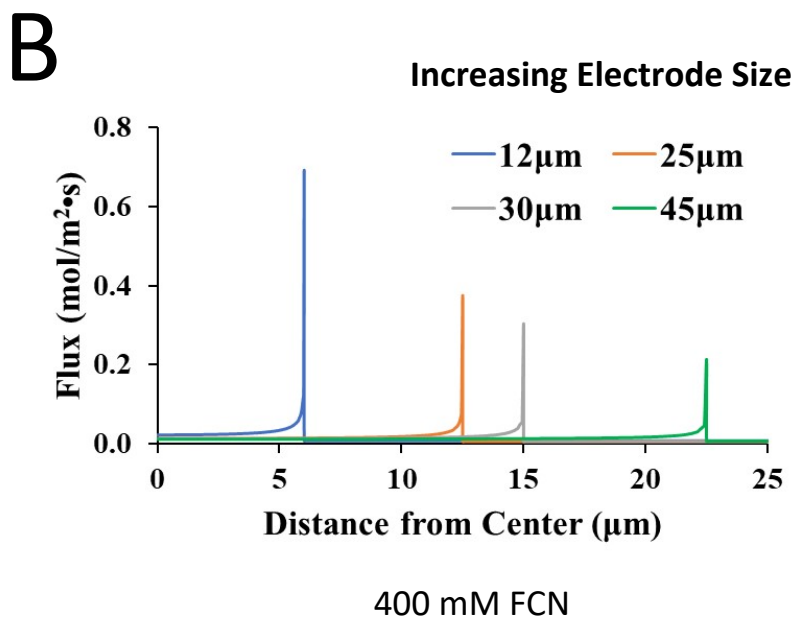
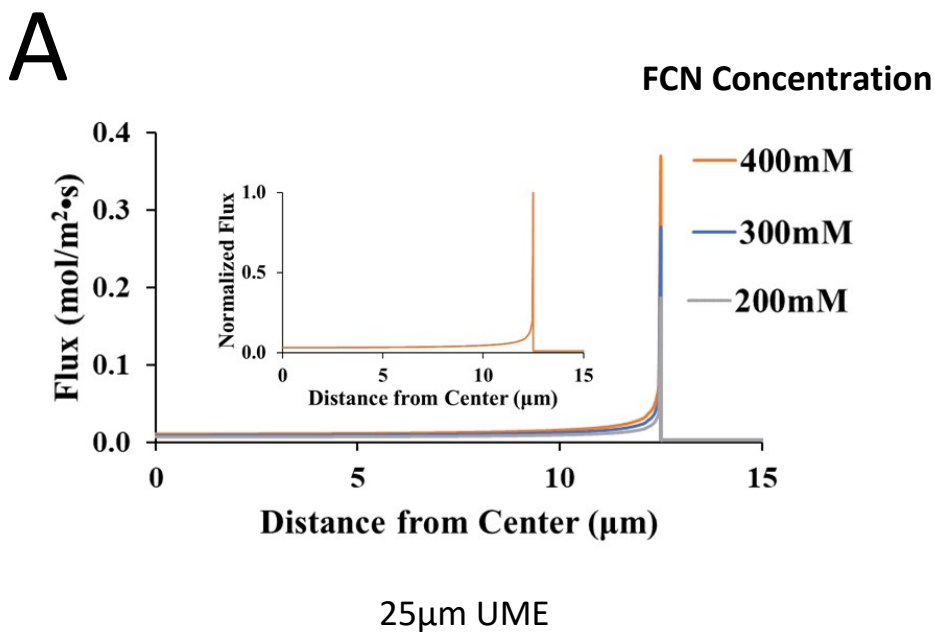


Figure S7. A) Redox flux along the radii of a UME $r_e = 12.5 \mu\text{m}$ with increasing FCN concentration. B) Redox flux along the radii of increasing UME radius and 400 mM FCN.

Flux disruption by $r_c = 2 \mu\text{m}$ at UME $r_e = 12.5 \mu\text{m}$ with various angle

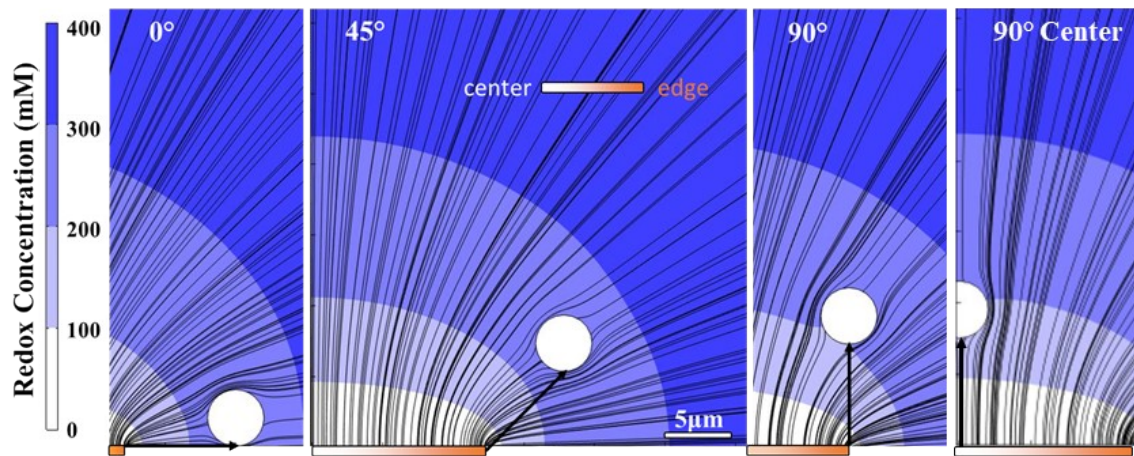


Figure S8. Simula
 $2 \mu\text{m}$ radius cell at
angle.

Table S1 Simulated Current vs. Experiment and Analytical Expression

% error of bare electrode currents (i_B) from simulation respect to experiments and equation S1 at different values of C_{FCN} for $r_e = 12.5 \mu\text{m}$.

C_{FCN} (mM)	Simulation (nA)	Experimental (nA)	% Error	Eq. S2 (nA)	% Error
200	736	723	1.8	646	13.9
300	1103	1070	3.1	970	13.7
400	1440	1420	1.4	1293	11.4

% error of bare electrode currents (i_B) from simulation respect to experiments and equation S1 as a function of r_e ($C_{FCN} = 400 \text{ mM}$).

r_e (mm)	Simulation (nA)	Experimental (nA)	% Error	Eq. S2 (nA)	% Error
6	666	645	3.3	621	7.2
12.5	1440	1420	1.4	1293	11.4
15	1804	1860	3.0	1551	16.3
22.5	2882	3060	5.8	2327	23.9

$$i_{ss} = 4nFD_{FCN}C_{FCN}r_e \quad (\text{S1})$$